

TEST REPORT

SGS-CSTC Standards Technical Services (Shanghai) Co., Ltd.

> No.588 West Jindu Road, Songjiang District, Shanghai, China



Page 2 of 11

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Testing laboratory SGS-CSTC Standards Technical Services (Shanghai) Co., Ltd.

Applicant's name...... Chinaland Solar Energy Co., Ltd.

Address..... Feidong New City Development Zone, Hefei, Anhui Province, P.R.China

Test specification Clause 10.1, 10.2, 10.3, 10.4 of IEC 61215:2005

Electroluminance test (EL), Potential Induced Degradation test (PID),

Test item description...... Photovoltaic (PV) module(s)

Trade mark.....: N/A

Manufacturer Same as applicant

Model/Type reference..... CHN260-72P

Ratings..... Refer to page 3

Signature

Tested by: Erin Lin

Signature

Approved by: Daniel Deng



Summary of testing

The submitted samples are tested according to clause 10.1, 10.2, 10.3, 10.4 of IEC 61215:2005 in this test report.

The samples have been tested and found to comply with the above-mentioned standards' requirements.

And the samples have been tested according to protocol testing methods of EL test, PID test by client's requirements.

The samples have been tested and found to comply with the client's requirement.

Tests performed (name of test and test clause):

IEC 61215:2005

10.1 Visual inspection

10.2 Maximum power determination

10.3 Insulation test

10.4 Measurement of temperature coefficients

Other tests:

EL test

PID test

Testing location:

Shanghai Institute of Quality Inspection and Technical Research

No.900 Jiangyue Road, Shanghai, China

Copy of marking plate / device under test:











Rear view of sample





General remarks

The test results presented in this report relate only to the object tested.

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"(See Enclosure #)" refers to additional information appended to the report.

"(See appended table)" refers to a table appended to the report.

Throughout this report a point is used as the decimal separator.

List of test equipment must be kept on file and available for review.

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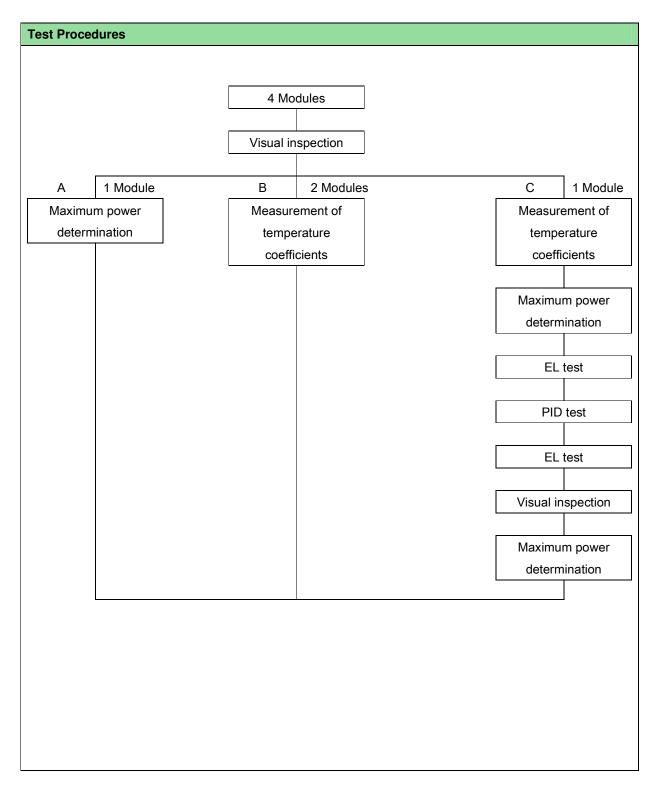
Unless otherwise stated: (a) the results shown in this document refer only to the sample(s) tested and (b) such sample(s) are retained for 3 months. This document cannot be reproduced except in full, without prior approval of the company.

General product information

The product is photovoltaic (PV) module.

All samples are polycrystalline silicon modules with 72 pieces of 156mm-side-length cell.







1. Test samples

Sample #	Model	Sample S/N
01	CHN260-72P	CHN1207450002
02	CHN260-72P	CHN1207450681
03	CHN260-72P	CHN1207450679
04	CHN260-72P	CHN1207450179

2. Test specification and test result

Group A	Group A						
10.1	TABLE: Visual inspection					_	
Test Date [MM/DD/YYYY]:			30	3/02/2012	_		
Sample #	Nature and posit	ion of initial f	ind	ndings – comments or attach photos			Verdict
01	No visual defects	3					Р
Supplementa	Supplementary information:						
10.2	TABLE: Maximum power of			rmination			_
Test Date [MM/DD/YYYY]:			08/02/2012			_	
Radiant source			\boxtimes				_
Module temperature [℃]:			25			_	
Irradiance [W/m²]:			1000				_
Sample #	Voc [V]	Isc [A]		Vmp [V]	Imp [A]	Pmp [W]	FF [%]
01	42.735	8.293		33.801	7.823	264.427	74.6
Supplementa	Supplementary information:						

Group B			
10.1	TABLE: Visual inspection		
Test Date [MM/DD/YYYY]		08/02/2012	_
Sample # Nature and position of initial fi		indings – comments or attach photos	Verdict
02	No visual defects		
03	No visual defects		
10.4	TABLE: Measurement of temperature coefficients		
Test Date [MM/DD/YYYY]:		08/02/2012	
Ambient air temperature [°C]:		25	
Irradiance [W/m²] high/low:		1000	
Module temperature [℃] high/low:		25.5/64.1, 25.2/64.4	



Sample #	Parameter	Calculated Value	_	
	α[%/°C] :	0.067		
02	β[%/℃] :	-0.292	_	
	δ [%/℃] :	-0.441	_	
	α[%/°C] :	0.063	_	
03	β[%/℃] :	-0.322	_	
	δ [%/℃] :	-0.416	_	
Supplementary information: Procedure with a solar simulator				

Group C							
10.1 Int TABLE: Visual inspection (Initial)						_	
Test Date [MM/DD/YYYY]:			0	7/31/2012	_		
Sample # Nature and position of initial fir			inc	dings – comment	ts or attach photo	os	Verdict
04 No visual defects							Р
Supplementa	ary information:						
10.4	TABLE: Measu	urement of te	m	perature coeffic	cients		
Test Date [M	M/DD/YYYY]	:	(7/31/2012			_
Ambient air te	emperature [℃]	:	2	25			_
Irradiance [W	//m²] high/low	:	1	000			_
Module temp	erature [℃] high	low:	2	25.5/61.0			_
Sample #	mple # Parameter			(_		
	α[%/°C] :		(0.064	_		
04	β[%/℃] :		-	-0.370			_
	δ [%/℃]	:	-	0.476			_
Supplementary information: Procedure with a				olar simulator			
10.2 Int	TABLE: Maxin	num power de	ete	ermination (Initi	ial)		_
Test Date [MM/DD/YYYY]:			C	08/02/2012			_
Radiant sour	ce			Solar simulator, Natural sunlight			_
Module temp	erature [℃]	·····:	2	25	_		
Irradiance [W/m²]:			1	000	_		
Radiant source							_
Sample #	Voc [V]	Isc [A]		Vmp [V]	Imp [A]	Pmp [W]	FF [%]
04	42.603 8.335			33.845	7.808	264.268	74.4
Supplementary information:							
	EL test (Initial)					
Test Date [MM/DD/YYYY]:			07/31/2012				_



Test Current	applied [A]	·····:	7	
Supplementa	ary information: a	bnormal cell w	as detected by EL test before PID	
	TABLE: PID te		·	_
Test Date [M	M/DD/YYYY] sta	rt/end:	08/03/2012 to 08/05/2012	_
Temperature [℃]: 85			_	
Humidity [%] 85			_	
Total hours [h] 48			_	
Voltage [V] : -1000				
Sample # Open circuits (yes/no)				
04 No				
Supplementa	ary information:			
(10.1 Visual	inspection afte	r PID test)		_
Test Date [M	M/DD/YYYY]	······································	08/06/2012	
Sample # Nature and position of initial findings – comments or attach photos				Verdict
04 No visual defects				Р
Supplementary information:				
(10.2 Maximum power determination after PID test)				
Test Date [MM/DD/YYYY]:			08/06/2012	_
Radiant sour	ce			_
·	erature [°C]		25	
	//m²]	:	1000	
Sample #	Voc [V]	Isc [A]	Vmp [V] Imp [A] Pmp [W]	FF [%]





Pmp degradation	after this too			1	
	anter triis tes	st [%] ≤ 5% :	•	3.38%	Р
Supplementary in	nformation:				
(EL test after PI	D test)				
Test Date [MM/DI	D/YYYY]	:	08/06/2012		
Test Current appli	ied [A]		7		_
Supplementary in	formation:				



3. List of measurement equipments

Identification#	Description
DZ-A-A2-0022	Pulse Solar Simulator
DZ-A-A1-0001-1	Standard solar cell
DZ-A-A2-0007-2	Dieletric Withstand Voltage tester
DZ-A-A1-0010	Thermal infrared imager
DZ-A-A1-50-26-0	Anemometer
DZ-A-A1-50-25-0	Pyranometer
DZ-A-A1-52-36-0	Data acquisition system
DZ-A-A3-0005	Walking-in environment chamber
DZ-A-A2-0007-1	Conductivity meter
DZ-A-A1-17-22-0	Thrust and tension meter
DZ-D-B2-0001	Solar cell infrared test equipment
DZ-A-A1-50-81-1	Analytical balance
DZ-A-A3-61-09-0	High temperature vacuum chamber

4. Statement of the estimated uncertainty of the test results

The estimated uncertainty fulfils the requirements from the CTL decision sheet DSH 251B / 2009.

---- End of Test Report -----